

Mercredi 19		Accueil, enregistrement, café, location skis	
	13:00-15:00		
	15:00-15:40	<b>F. Carbone</b>	<i>Time-resolved EELS of surfaces and thin films</i>
	15:40-16:00	L Calmels	Atomic site sensitivity of the energy loss magnetic chiral dichroic (EMCD) spectra of complex oxides
	16:00-16:20	P Krüger	L23-edge spectra calculated with multichannel multiple scattering theory
	16:20-16:40	Yedra	Development of a New Software Application
	16:40-17:20	<b>V. Mauchamp</b>	Les effets d'excitation en EELS : de l'équation de Bethe-Salpeter à l'approximation monoélectronique
	17:30-19:00	Posters	
	19:30	Apero	
	20:00	Dinner	
Jeudi 20	08:40-09:20	<b>S. Marco</b>	<i>3D chemical mapping by EFTEM and SNR improvement by PCA and its interest in material and biological sciences</i>
	09:20-09:40	M Walls	An application of independent component analysis in EELS: Mapping titanium and tin oxide phases
	09:40-10:00	P de Coux	Structural properties of epitaxial ferromagnetic
	10:00-10:20	R Ejarrat	Quantitative VEELS Characterization of InAlN/GaN Distributed Bragg
	10:20-10:50	Café	
	10:50-11:30	<b>J-C Lebossé</b>	
	11:30-11:50	F de la Pena	Advanced methods for EELS analysis; presenting EELSLab
	11:50-12:10	M.-L. David	Nano-cavités créées par implantation d'hélium dans du silicium
	12:40-16:30	Libre/Déjeuner	
	16:30-17:00	Café	
	17:00-17:40	<b>U. Kaiser</b>	
	17:40-18:00	R Arenal	EELS Measurements on Heteroatomic Nanotubes
	18:00-18:20	J. Danet	L'EELS : Des alliages Li <sub>x</sub> Si aux alliages Na <sub>x</sub> Si
	18:20-18:50	FEI	
	18:50-19:20	Gatan, V. Richard	Dernières évolutions du filtre post-colonne Gatan (Quantum)
19:20-19:50	Jeol, T. Oikawa	Newly developed cold field emission gun for TEM	
	20:00	Dinner	
Vendredi 21	08:20-09:00	<b>Laura Bocher</b>	
	09:00-09:20	M. Bugnet	Comportement de Ti <sub>3</sub> AlC <sub>2</sub> sous irradiation aux ions : apport
	09:20-09:40	DL Alexander	
	09:40-10:10	ZEISS	
	10:10-10:30	Café	
	10:30-11:10	<b>Philippe Moreau</b>	
	11:10-11:30	M. Gauthier	Caractérisation MET/EELS d'Electrodes Négatives à base de Silicium pour les Batteries
	11:30-11:50	F. Pailloux	Etude de films minces de BiFeO <sub>3</sub> par microscopie électronique en transmission
	11:50-12:10		
12:10-12:30	Concluding remarks		
	12:30	lunch	